

ABSTRACT

PROBE CARD

5 A probe card includes probes that are made of a
conductive material and come into contact with the
semiconductor wafer to receive or output an electric
signal; a probe head that holds the probes; a substrate
that has a wiring pattern corresponding to the circuit
10 structure for generating a signal for a test; a reinforcing
member that reinforces the substrate; an interposer that is
stacked on the substrate for connection of wires of the
substrate; a space transformer that is stacked between the
interposer and the probe head and transforms intervals
15 among the wires; and a plurality of first post members that
have a height greater than a thickness of the substrate,
and are embedded in a portion of the substrate on which the
interposer is stacked.

20 Fig. 3